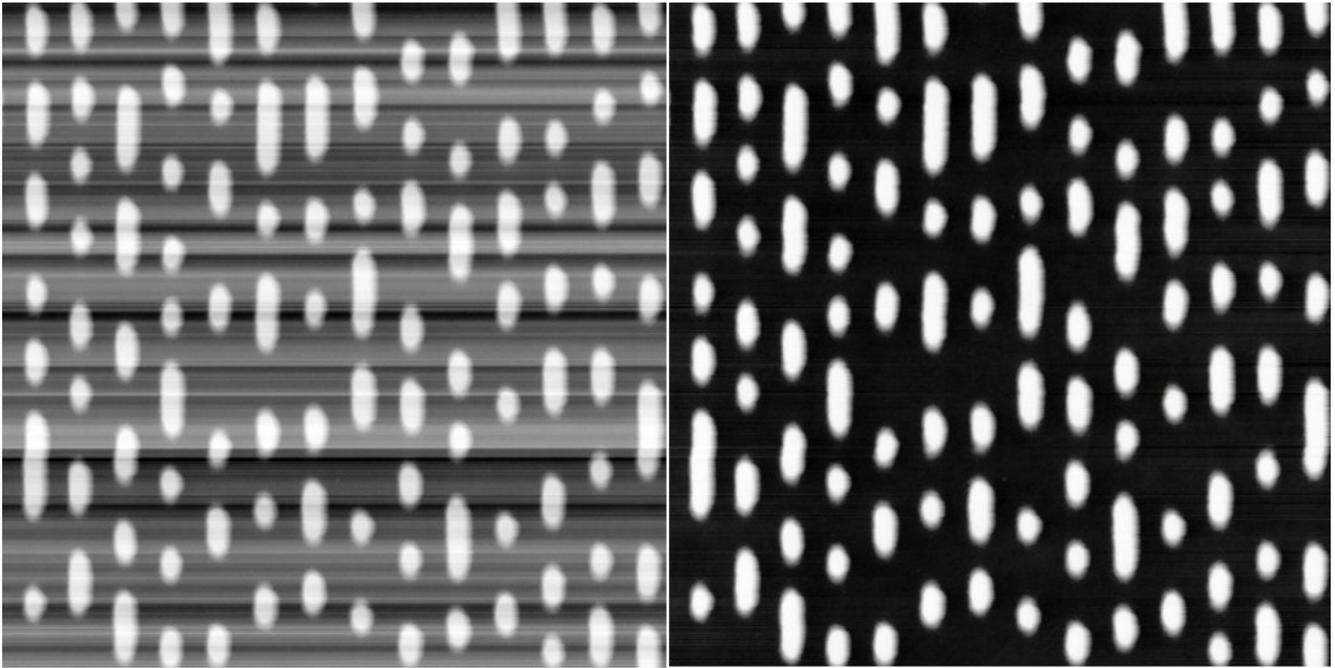


VASTLY IMPROVE IMAGES FOR MEASUREMENT

Change This:

To This:



Warped samples, static electrical charges, and other problems can result in AFM images looking like the one on the left. **It is nearly impossible to get accurate measurements from such images.** Yet with the Smart Flatten™ feature in the **DTP Advanced Image Processor™** by Advanced Surface Microscopy, Inc. the image can be cleaned up. The cleaned image can then be saved and measurements can be made either manually with NanoScope® AFM software or automatically with DiscTrack Plus™.

You can make useful measurements from images that previously would have to be discarded and recaptured. This saves you time. **This saves your company money.**

The Advanced Image Processor can also be used to **import files** from many popular graphics formats and **convert them** to a form that can be read by DiscTrack Plus. Optical Microscopes, SEMs, and other instruments can now benefit from the measurement technology in DiscTrack Plus.



**Advanced Surface
Microscopy, Inc.**

3250 N Post Rd, Ste 120
Indianapolis, IN 46226, U.S.A.
Phone: 317-895-5630
Toll free: 800-374-8557
Fax: 317-895-5652
e-mail: info@asmicro.com
web: <http://www.asmicro.com>